

Notice of References Cited	Application/Control No. 10/643,078	Applicant(s)/Patent Under Reexamination NAKAZAWA ET AL.	
	Examiner David Q. Nguyen	Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,646,449	11-2003	Seppinen et al.	324/624
*	B	US-6,292,519	09-2001	Popovic, Branislav M.	375/346
*	C	US-6,885,694	04-2005	He et al.	375/144
*	D	US-2005/0032472	02-2005	Jiang et al.	455/013.4
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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